

ResMap 168Freesed and the set of the set of

Wafer handling:	Auto cassette load
Wafer Size:	4"- 8" auto load; 2"- 8" manual load
Max Diameter:	8.2"
Max Square:	5.8" x 5.8"; 156mm x 156mm
Typical Measurement Time:	1 second per site
Typical Wafer Handling Time:	10 seconds each way
Typical Notch Find Time:	12 seconds with optional notch finder
Maximum Throughput:	40 wph (49 sites); 80 wph (5 sites)
Measurement Range:	$2 \text{ m}\Omega/\Box - 5 \text{ M}\Omega/\Box$ (can be optimized to $1 \text{ m}\Omega/\Box$)
Repeatability (1σ, typical):	$\leq \pm 0.02\%$ (static or Rs pack); $\leq \pm 0.1\%$ (dynamic nearby spots)
Accuracy:	$\leq \pm 0.5\%$ using NIST traceable ResCal standards

Minimum Edge Exclusion:	1.5mm (center of probe to edge of film)
Computer System:	Pentium class; Windows XP Home (display not included)
SECS-II Option:	Available
Mapping Patterns:	Polar map (align with notch/flat, straddle, or follow flat); rectangular map (choose inside edge exclusion); line scan (diameter, radius or any point to point along diameter, minimum step 0.1mm); user defined (template)
Plots:	Contour (spacing choice, $1/3\sigma$, fixed and auto %), 3D, line, data map, histogram, data sequence, radial and angular distributions; various modes of trend charts available
Data:	All ResMap data files may be ported to programs such as Excel® for further analysis.

Facilities	
House Vacuum :	Required; >500 mm Hg, on ¼" OD flexible tubing
AC Power:	100V to 240V < 10 KVA
Size (inches): width x depth x height	12" w x 28"d x 10"h; tabletop (table not included)

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